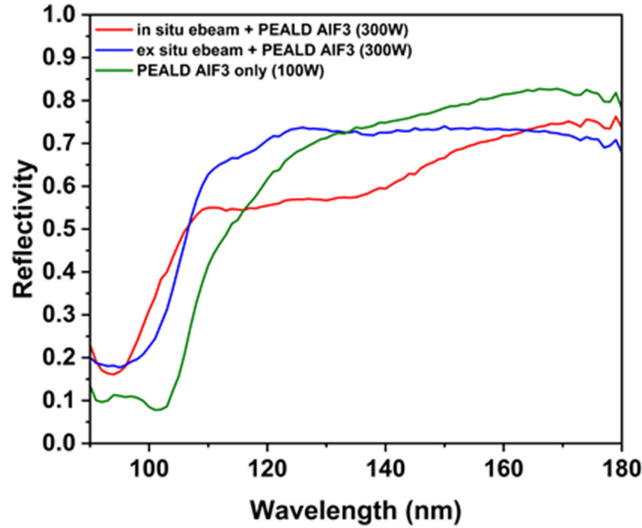

Fig. 1: FUV measurements comparing the performance of ~20nm AlF_3 films processed with PEALD only (green), ex situ ebeam and PEALD process (blue), and in situ ebeam and PEALD process (red).

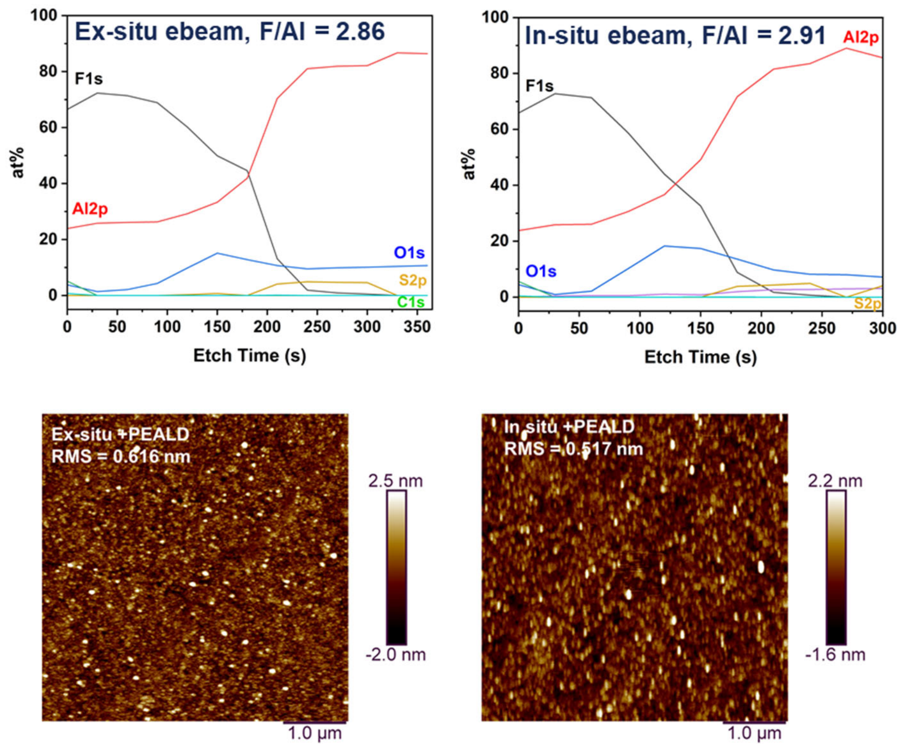

Fig. 2: XPS depth profile and AFM images comparing AlF_3 films on Al mirrors fabricated using an in situ ebeam and PEALD process with an ex situ ebeam and PEALD process.